International Rectifier

IRFR3806PbF IRFU3806PbF

Applications

- High Efficiency Synchronous Rectification in SMPS
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits

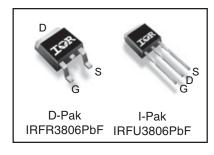
G

HEXFET® Power MOSFET 60V

V_{DSS}		60V
R _{DS(on)}	typ.	12.6m $Ω$
	max.	15.8m $Ω$
I _D		43A

Benefits

- Improved Gate, Avalanche and Dynamic dv/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dl/dt Capability



G	D	S
Gate	Drain	Source

Absolute Maximum Ratings

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, VGS @ 10V	43	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	31	А
I _{DM}	Pulsed Drain Current ①	170	
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	71	W
	Linear Derating Factor	0.47	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
dv/dt	Peak Diode Recovery ③	24	V/ns
T_J	Operating Junction and	-55 to + 175	°C
T _{STG}	Storage Temperature Range		
	Soldering Temperature, for 10 seconds	300	
	(1.6mm from case)		

Avalanche Characteristics

E _{AS (Thermally limited)}	Single Pulse Avalanche Energy ②	73	mJ
I _{AR}	Avalanche Current ①	25	Α
E _{AR}	Repetitive Avalanche Energy ④	7.1	mJ

Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case ®		2.12	
$R_{\theta CS}$	Case-to-Sink, Flat Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient ⑦®		62	

Static @ $T_J = 25$ °C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	60			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.075		V/°C	Reference to 25°C, I _D = 5mA ^①
$R_{DS(on)}$	Static Drain-to-Source On-Resistance		12.6	15.8	mΩ	$V_{GS} = 10V, I_D = 25A \oplus$
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 50\mu A$
I _{DSS}	Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 60V$, $V_{GS} = 0V$
				250		$V_{DS} = 48V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I_{GSS}	Gate-to-Source Forward Leakage			100	nA	$V_{GS} = 20V$
	Gate-to-Source Reverse Leakage			-100		$V_{GS} = -20V$

Dynamic @ T_J = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	41			S	$V_{DS} = 10V, I_D = 25A$
Q_g	Total Gate Charge		22	30	nC	I _D = 25A
Q_{gs}	Gate-to-Source Charge		5.0			$V_{DS} = 30V$
Q_{gd}	Gate-to-Drain ("Miller") Charge		6.3			V _{GS} = 10V ⊕
Q _{sync}	Total Gate Charge Sync. (Q _g - Q _{gd})		28.3			$I_D = 25A, V_{DS} = 0V, V_{GS} = 10V$
$R_{G(int)}$	Internal Gate Resistance		0.79		Ω	
$t_{d(on)}$	Turn-On Delay Time		6.3		ns	$V_{DD} = 39V$
t _r	Rise Time		40			I _D = 25A
$t_{d(off)}$	Turn-Off Delay Time		49			$R_G = 20\Omega$
t _f	Fall Time		47			V _{GS} = 10V ⊕
C _{iss}	Input Capacitance		1150			$V_{GS} = 0V$
C _{oss}	Output Capacitance		130			$V_{DS} = 50V$
C_{rss}	Reverse Transfer Capacitance		67		рF	f = 1.0 MHz
C _{oss} eff. (ER)	Effective Output Capacitance (Energy Related)@		190			V _{GS} = 0V, V _{DS} = 0V to 60V ©
C _{oss} eff. (TR)	Effective Output Capacitance (Time Related)®		230			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 60V $

Diode Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
I _S	Continuous Source Current			43	Α	MOSFET symbol	
	(Body Diode)					showing the	
I _{SM}	Pulsed Source Current			170		integral reverse	
	(Body Diode) ①					p-n junction diode.	
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$, $I_S = 25A$, $V_{GS} = 0V$ ④	
t _{rr}	Reverse Recovery Time		22	33	ns	$T_J = 25^{\circ}C$ $V_R = 51V$,	
			26	39		$T_J = 125^{\circ}C$ $I_F = 25A$	
Q_{rr}	Reverse Recovery Charge		17	26	nC	$T_J = 25^{\circ}C$ di/dt = 100A/ μ s $\textcircled{4}$	
			24	36		$T_J = 125^{\circ}C$	
I _{RRM}	Reverse Recovery Current		1.4		Α	$T_J = 25^{\circ}C$	
t _{on}	Forward Turn-On Time	Intrins	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Limited by T_{Jmax} , starting T_J = 25°C, L = 0.23mH R_G = 25 Ω , I_{AS} = 25A, V_{GS} =10V. Part not recommended for use above this value.
- $\label{eq:loss_distance} \ensuremath{\Im} \ I_{SD} \leq 25A, \ di/dt \leq 1580A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \ T_J \leq 175^{\circ}C.$
- 4 Pulse width \leq 400 μ s; duty cycle \leq 2%.

- $^{\circ}$ C_{oss} eff. (ER) is a fixed capacitance that gives the same energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.
- $\ensuremath{\$}\ \ensuremath{\mathsf{R}}_{\theta}$ is measured at T_J approximately 90°C.

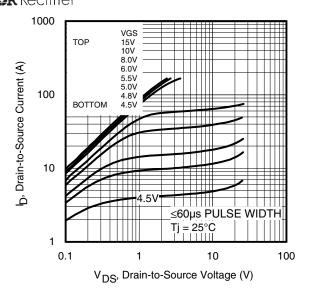


Fig 1. Typical Output Characteristics

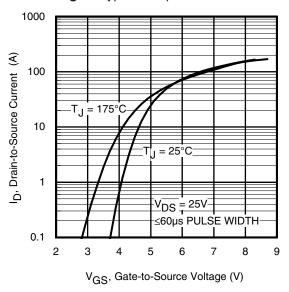


Fig 3. Typical Transfer Characteristics

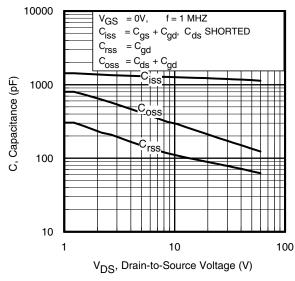


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage www.irf.com

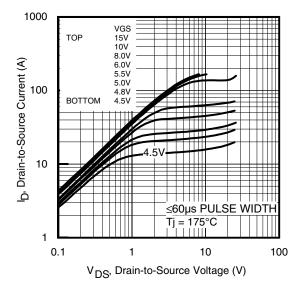


Fig 2. Typical Output Characteristics

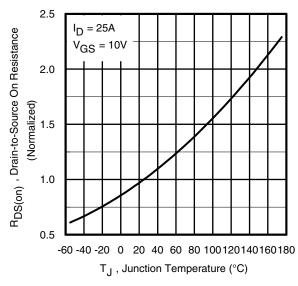


Fig 4. Normalized On-Resistance vs. Temperature

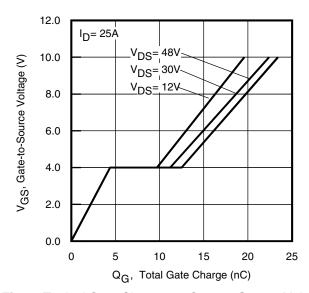


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

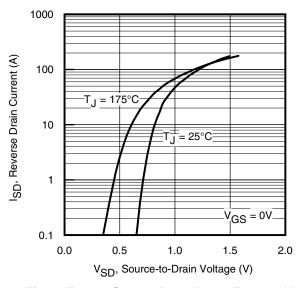


Fig 7. Typical Source-Drain Diode Forward Voltage

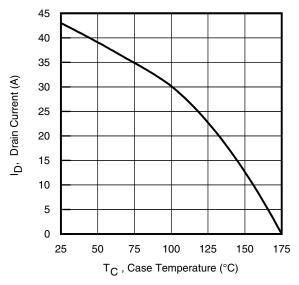


Fig 9. Maximum Drain Current vs. Case Temperature

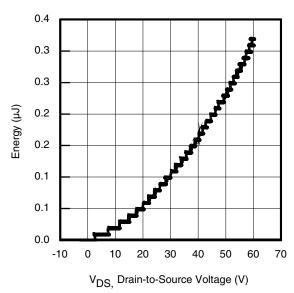


Fig 11. Typical C_{OSS} Stored Energy

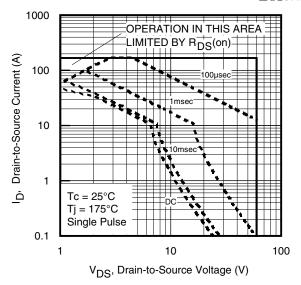


Fig 8. Maximum Safe Operating Area

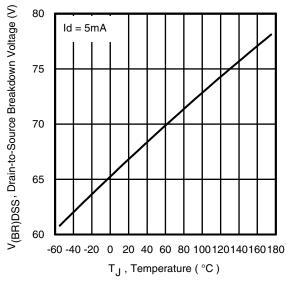


Fig 10. Drain-to-Source Breakdown Voltage

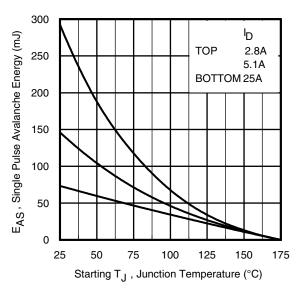


Fig 12. Maximum Avalanche Energy vs. DrainCurrent www.irf.com

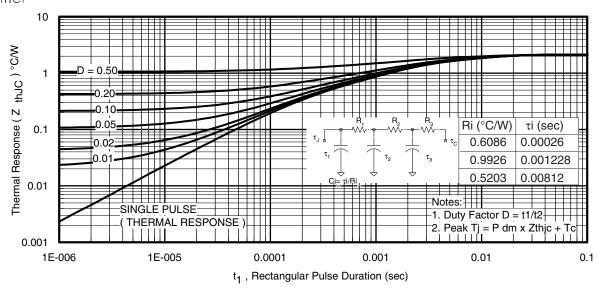


Fig 13. Maximum Effective Transient Thermal Impedance, Junction-to-Case

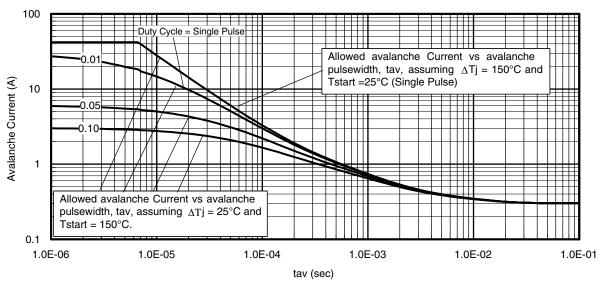


Fig 14. Typical Avalanche Current vs. Pulsewidth

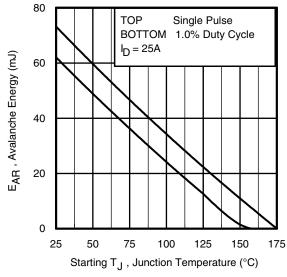


Fig 15. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves, Figures 14, 15: (For further info, see AN-1005 at www.irf.com)

- 1. Avalanche failures assumption:
- Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long asT_{imax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 16a, 16b.
- 4. P_{D (ave)} = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 14, 15).

t_{av =} Average time in avalanche.

D = Duty cycle in avalanche = $t_{av} \cdot f$

 $Z_{th,JC}(D, t_{av})$ = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2\Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$

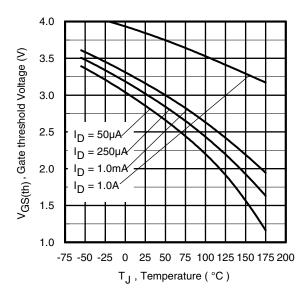


Fig 16. Threshold Voltage vs. Temperature

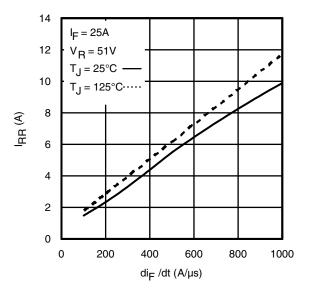


Fig. 18 - Typical Recovery Current vs. dif/dt

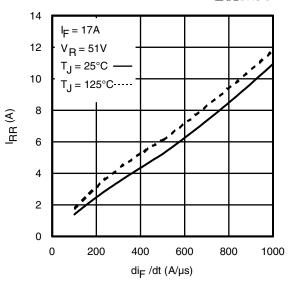


Fig. 17 - Typical Recovery Current vs. di_f/dt

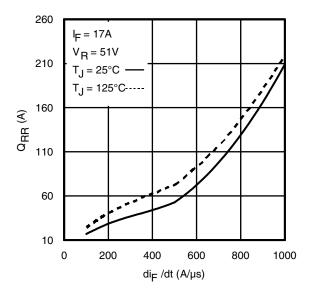


Fig. 19 - Typical Stored Charge vs. dif/dt

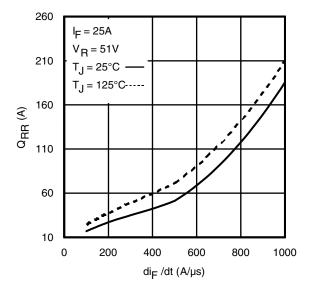


Fig. 20 - Typical Stored Charge vs. dif/dt

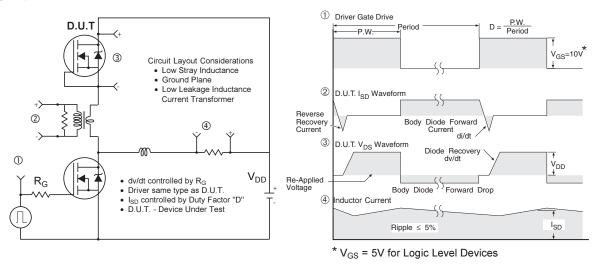


Fig 20. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

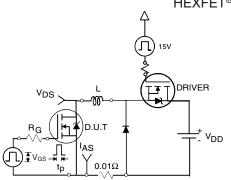


Fig 21a. Unclamped Inductive Test Circuit

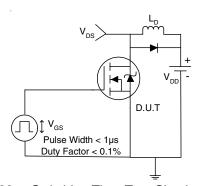


Fig 22a. Switching Time Test Circuit

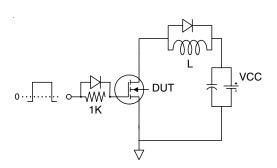


Fig 23a. Gate Charge Test Circuit www.irf.com

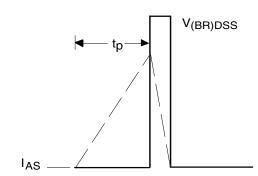


Fig 21b. Unclamped Inductive Waveforms

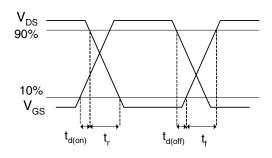


Fig 22b. Switching Time Waveforms

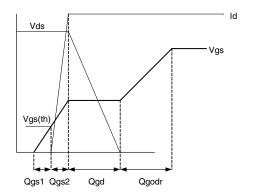


Fig 23b. Gate Charge Waveform

IRFR/U3806PbF

<u></u>

4

D-Pak (TO-252AA) Package Outline

Dimensions are shown in millimeters (inches)

⊕ .010 **(** C A B

F L3 ⚠

B

b 🙆

-2× b ⊕ .010@ C A B

LEAD TIP





₽ 🛦 SEATING PLANE

SECTION C-C

INTERNATIONAL

RECTIFIER

LOGO

ASSEMBLY

LOT CODE

DETAIL "C" ROTATED 90" CE SCALE: 20:1

THERMAL PAD

1/4

(DATUM A)

- 1 DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- 3- LEAD DIMENSION UNCONTROLLED IN L5.
- A- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.- SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- 📤- DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- DIMENSION 61 & c1 APPLIED TO BASE METAL ONLY.
- A- DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

S Y M		DIMENSIONS					
B	MILLIM	ETERS	INC	HES	O T E S		
0 L	MIN.	MAX.	MIN.	MAX.	E S		
Α	2.18	2.39	.086	.094			
A1	-	0.13	-	.005			
ь	0.64	0.89	.025	.035			
ь1	0.65	0.79	.025	.031	7		
b2	0.76	1.14	.030	.045			
b3	4.95	5.46	.195	.215	4		
С	0.46	0.61	.018	.024			
c1	0.41	0.56	.016	.022	7		
c2	0.46	0.89	.018	.035			
D	5.97	6.22	.235	.245	6		
D1	5.21	-	.205	-	4		
Ε	6.35	6.73	.250	.265	6		
E1	4.32	-	.170	-	4		
е	2.29	BSC	.090	BSC			
н	9.40	10.41	.370	.410			
L	1.40	1.78	.055	.070			
L1	2.74	BSC	.108	REF.			
L2	0.51	BSC	.020	BSC			
L3	0.89	1.27	.035	.050	4		
L4	_	1.02	-	.040			
L5	1,14	1.52	.045	.060	3		
ø	0.	10*	0.	10*			
ø1	0,	15°	0.	15°			
ø2	25°	35*	25°	35°			

IRFR120

IQR 116A

34

LEAD ASSIGNMENTS

HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE 4.- DRAIN

IGBT & CoPAK

1.- GATE

PART NUMBER

DATE CODE

WEEK 16 LINE A

YEAR 1 = 2001

- 2.- COLLECTOR 3.- EMITTER
- 4. COLLECTOR

D-Pak (TO-252AA) Part Marking Information

EXAMPLE: THIS IS AN IRFR120

WITH ASSEMBLY LOT CODE 1234

VIEW A-A

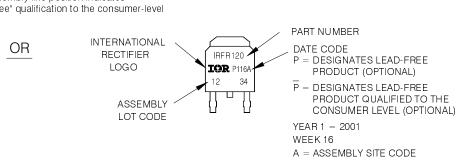
ASSEMBLED ON WW 16, 2001

IN THE ASSEMBLY LINE "A"

Note: "P" in assembly line position indicates "Lead-Free"

"P" in assembly line position indicates

"Lead-Free" qualification to the consumer-level



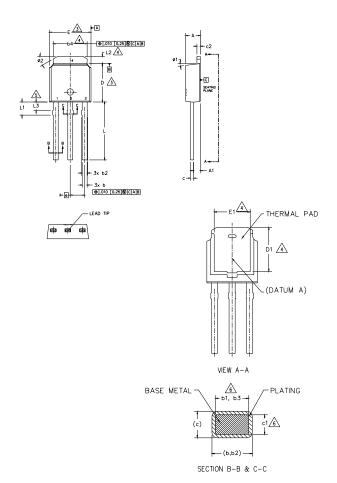
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

8 www.irf.com

www.irf.com

I-Pak (TO-251AA) Package Outline

Dimensions are shown in millimeters (inches)



NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- ⚠ DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1.
- ⚠- LEAD DIMENSION UNCONTROLLED IN L3.
- A- DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.
- 7.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA (Date 06/02).
- 8.- CONTROLLING DIMENSION : INCHES.

S Y						
М		DIMEN	SIONS		N	
B	MILLIM	MILLIMETERS		HES	O T E S	
L	MIN.	MAX.	MIN.	MAX.	Š	
Α	2.18	2.39	.086	.094		
Α1	0.89	1,14	.035	.045		
ь	0.64	0.89	.025	.035		
ь1	0.65	0.79	.025	.031	6	
b2	0.76	1.14	.030	.045		
ь3	0.76	1.04	.030	.041	6	
b4	4.95	5.46	.195	.215	4	
С	0.46	0.61	.018	.024		
c1	0.41	0.56	.016	.022	6	
c2	0.46	0.89	.018	.035		
D	5.97	6.22	.235	.245	3	
D1	5.21	-	.205	-	4	
Ε	6.35	6.73	.250	.265	3	
E1	4.32	-	.170	-	4	
е	2.29	BSC	.090 BSC			
L	8.89	9.65	.350	.380		
L1	1.91	2.29	.045	.090		
L2	0.89	1.27	.035	.050	4	
L3	1.14	1.52	.045	.060	5	
ø1	0,	15*	0,	15*		
ø2	25*	35*	25*	35*		
	-					

LEAD ASSIGNMENTS

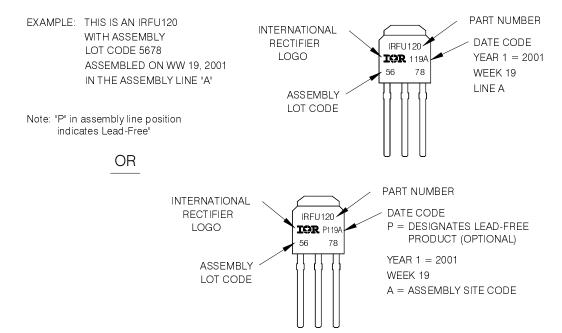
HEXFET

1.- GATE

2.- DRAIN

3.- SOURCE 4.- DRAIN

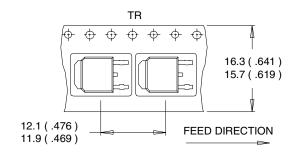
I-Pak (TO-251AA) Part Marking Information

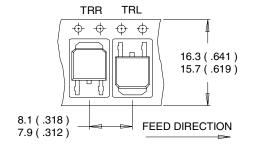


Note: For the most current drawing please refer to IR website at $\underline{http://www.irf.com/package/}$

D-Pak (TO-252AA) Tape & Reel Information

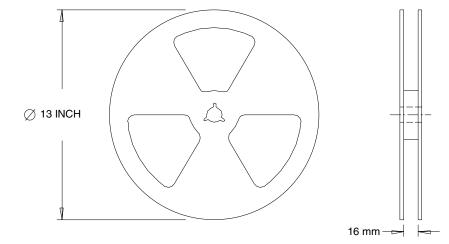
Dimensions are shown in millimeters (inches)





NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market.

Qualification Standards can be found on IR's Web site.

